Abstracts

A Non-Contacting Probe for Measurements on High-Frequency Planar Circuits

S.S. Osofsky and S.E. Schwarz. "A Non-Contacting Probe for Measurements on High-Frequency Planar Circuits." 1989 MTT-S International Microwave Symposium Digest 89.2 (1989 Vol. II [MWSYM]): 823-825.

A novel probe for internal measurements on high-frequency planar circuits has been designed and tested. It requires no electrical contact with the circuit and has little or no effect on the circuit under test. Amplitudes and phases of currents at arbitrary positions can be measured. Using microfabrication techniques, working probes have been constructed for measurements in the 26.5-40 GHz band. Performance characteristics and typical measurements will be described. Direct measurements obtained with these probes provide new information on internal circuit operation: The technique can also be applied to rapid production testing.

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